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Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023 Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number						
		BAT54CY						
		Part Description						
		Nexperia DHAM Schottky SMD package						
								Test Conditions
			TEST				,	
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		1ESD22-A113	,,,,,		un purco	bee below		
		Bake Tamb = 125 °C	24 hours					
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours					
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0		
	5	MIL-STD-750-1						
	HTRB	M1038 Method A						
		Tj = Tjmax, Vr = 100% of max. datasheet						
# B1	Bias	reverse voltage ^[1]	1000 hours	206	9320	0		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	311	14080	0		
	, , ,							
	UHAST	JESD22-A118						
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %						
		JESD22-A102	96 hours	311	14080	0		
	AC	Tamb = $121 ^{\circ}C$, RH = $100 ^{\circ}M$						
# A3 alt	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$						
, no are								
	H3TRB	JESD22-A101						
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of						
# A2 alt	Temperature Reverse Bias		1000 hours	311	14080	0		
# 712 UIC		MIL-STD-750 Method 1037	2000 110010	011	1.000	0		
	IOL	ton = toff, devices powered to insure ΔT_j =						
# A5	Intermittent Operating Life		1000 hours	312	14120	0		
			2000 110010	512	- 1120	-		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	269	8070	0		
,	SD	200 0-0 0	10.5	205	0070	0		
# C10	Solderability	J-STD-002		222	6660	0		
	,	des have to be considered (thermal runaway).		~~~	0000	0		

[1] The physical limitations of Schottky diodes have to be considered (thermal runaway). [2] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Nexperia DHAM Schottky 9320 0 0,46 2,19E+09	Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
DHAM Schottky 9320 0 0,46 2,19E+09						
	DHAM	Schottky	9320	0	0,46	2,19E+09

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